

U.S. Department of Commerce

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APPLICANT: Wo -Sup SHIN

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GROUP 1763

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if appropriate
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ADP	0 586 147	03/1994	Europe	—	—	English
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ADP	1-189631	07/1989	Japan	—	—	Abstract
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Examiner Signature: *Mia Powell*Date Considered: *7/27/00*

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ADP		2-138459	11/1990	Japan			No
ADP		3-22390	01/1991	Japan			Abstract
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Examiner Signature: Sue C. Howell

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APPLICANT

Woo Sup SHIN, et al.

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LIST OF REFERENCES CITED BY APPLICANT
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	AC						JAN 20 2000
	AD						PTENT & TRADEMARK OFFICE
	AE						

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<i>SLB</i>	AL	36 11 387	10/15/87	Germany		✓
<i>SLB</i>	AY	38 53 904	10/12/95	Germany		✓
<i>SLB</i>	AN	60-163435	08/26/85	Japan		✓
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EXAMINER *Reva C Powell*

DATE CONSIDERED

3-27-00

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